



**TS IEC 62804-1:2015**  
**Photovoltaic (PV) Modules - Test Methods for the detection of potential-induced  
degradation (PID)**  
**Part 1: Crystalline silicone  
Confirmation of test results**

**VDE Renewables File Ref.: 10011/ET-20201127-293-1**

**Applicant:** Wuxi Suntech Power Co., Ltd.  
16 Xin Hua Road, 214028 Wuxi City, China.

**Product:** Crystalline silicon Photovoltaic (PV)-Modules

**Type:** A) STPXXXS-C72/Vmh  
B) STPXXXS-C66/Wmh  
C) STPXXXS-C54/Umh STPXXXS-C54/Umhm

XXX in the type replaces the power in watt and can be any number  
between: 525 - 550 for A), 480 - 500 for B), 390 - 410 for C)

**Manufacturer:** **Wuxi Suntech Power Co., Ltd.**

**Standard:** TS IEC 62804-1:2015

**Test conditions**

Testing time:	192 h
Chamber temperature:	85°C
Relative Humidity:	85 %
Potential to ground:	± 1500 V

**Pass criteria**

Power degradation:	< 5%
Dry Insulation:	> 40 MΩm <sup>2</sup>
Wet insulation:	> 40 MΩm <sup>2</sup>



### Summary of test results:

<b>Maximum power degradation:</b>	allowed	max. 5 %
	measured	max. 0.71%

The measured degradation is below the allowed degradation.

<b>Dry insulation resistance:</b>	required	min. 15.5 MΩ
	measured	>500 MΩ

The measured dry insulation resistance is above the limit.

<b>Wet insulation resistance:</b>	required	min. 15.5 MΩ
	measured	>500 MΩ

The measured wet insulation resistance is above the limit.

<b>Visual inspection:</b>	No findings
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The complete test results and the relevant bill of materials are given in Test Report No.: TRPVM- ET-20201127-293-1.

**VDE Renewables GmbH**

  
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